

# ***Digital Photography IX***

**Nitin Sampat**  
**Sebastiano Battiato**  
*Editors*

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P.O. Box 10, Bellingham, Washington 98227-0010 USA

Telephone +1 360 676 3290 (Pacific Time) · Fax +1 360 647 1445

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and

**IS&T—The Society for Imaging Science and Technology**

7003 Kilworth Lane, Springfield, Virginia, 22151 USA

Telephone +1 703 642 9090 (Eastern Time) · Fax +1 703 642 9094

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